

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

CORRECTED VERSION

(19) World Intellectual Property  
Organization  
International Bureau



(43) International Publication Date  
31 December 2003 (31.12.2003)

PCT

(10) International Publication Number  
WO 2004/001433 A1

(51) International Patent Classification<sup>7</sup>: G01R 31/3185

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(21) International Application Number:  
PCT/IB2003/002387

(22) International Filing Date: 5 June 2003 (05.06.2003)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:  
02077495.6 21 June 2002 (21.06.2002) EP

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(81) Designated States (national): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NI, NO, NZ, OM, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

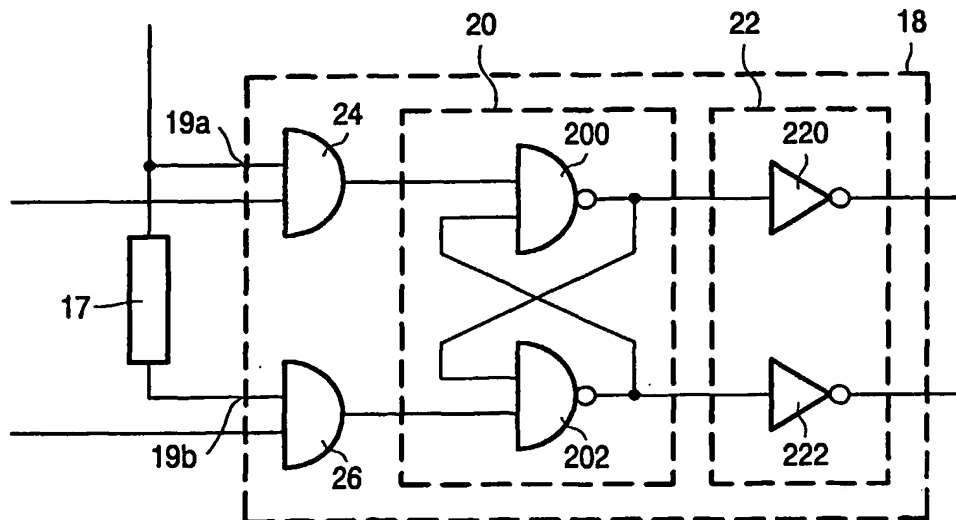
(84) Designated States (regional): ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Published:

— with international search report

[Continued on next page]

(54) Title: ELECTRONIC CIRCUIT WITH ASYNCHRONOUSLY OPERATING COMPONENTS



(57) Abstract: An electronic circuit that comprises components that operate asynchronously of one another. An interface element has inputs coupled to a respective one of the components. The interface element supplies a logic output signal that is a logic function of signals at the inputs and dependent on the relative timing of the signals at the inputs. The electronic circuit is switched to a test mode, in which test input signals are applied to the electronic circuit from a test signal source. During test a difference is caused to occur between the time intervals after which the test signal source affects different ones of the signals at the inputs of the interface element. Preferably the test control circuit activates said difference in the test mode and not in the normal operating mode.

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